

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/194,164	DAN ET AL.
	Examiner	Art Unit
	Christopher H. Yaen	1642

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated searches	5/13/2005	CHY
Plam Inventor search	5/13/2005	CHY
stic interference search SEQ ID No: 13, 14	5/13/2005	CHY
Patent conf: J. Siew and J. Housel	4/28/2005	CHY

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
536	23.1	5/13/2005	CHY
530	387.1	5/13/2005	CHY
stic SEQ ID No: 13,14			